

Notice of References Cited	Application/Control No.		Applicant(s)/Patent Under Reexamination	
	10/605,234		CHIH-HAN CHANG	
	Examiner		Art Unit	Page 1 of 1
Khiem D Nguyen		2823		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,316,310	11-2001	Wensley et al.	438/249
*	B	US-2004/0016951	01-2004	Mizushima, Ichiro	257/304
*	C	US-2002/0090780	07-2002	Divakaruni et al.	438/246
*	D	US-2002/0089007	07-2002	Divakaruni et al.	257/302
*	E	US-2002/0064913	05-2002	Adkisson et al.	438/241
*	F	US-2002/0016035	02-2002	Wu et al.	438/243
*	G	US-6,034,390	03-2000	Tews, Helmut	257/301
*	H	US-6,723,611	04-2004	Akatsu et al.	438/386
*	I	US-6,486,024	11-2002	Tews et al.	438/249
*	J	US-6,310,375	10-2001	Schrems, Martin	257/301
*	K	US-2004/0048441	03-2004	Akatsu et al.	438/386
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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